



Attorney Docket No.: 205-007US2

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: David E. Wolf et al. Art Unit: 1743  
Serial No.: 10/632,725 Examiner:  
Filed: August 1, 2003  
Title: METHOD OF MEASURING MOLECULAR INTERACTIONS

Mail Stop NON-FEE AMENDMENT  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

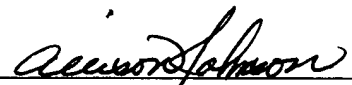
Applicants submit the two (2) references listed on the attached form PTO-1449, copies of which are enclosed. Applicants request that the Examiner initial each entry and return a copy of the initialed Form 1449 form to Applicants.

This statement is being filed pursuant to 37 CFR 1.97(b)(3) before the mailing of a first Office action on the merits.

Please apply any fees owing or credit any overpayment to Deposit Account No.501,171.

Respectfully submitted,

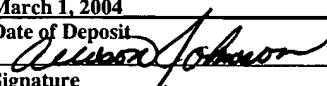
Date: March 1, 2004

  
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**CERTIFICATE OF MAILING BY FIRST CLASS MAIL**

I hereby certify under 37 CFR §1.8(a) that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage on the date indicated below and is addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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Allison Johnson  
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Substitute Form 1449

**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT**

Sheet 1

Of 1

Application Number	10/632,725
Filing Date	8/1/2003
First Named Inventor	David E. Wolf et al.
Art Unit	1743
Examiner Name	
Attorney Docket No.	205-007US2

**U.S. PATENT DOCUMENTS**

Examiner Initials	Cite No.	Document No.	Publication Date	Patentee or Applicant	Pages, Column, Lines, Where Relevant Passages Or Relevant Figures Appear
	AA	US-2002/0142335 A1	10/03/02	Strittmatter	
	AB	US-2002/0152479 A1	10/17/02	Lehmann et al.	
	AC	US-			
	AD	US-			
	AE	US-			
	AF	US-			
	AG	US-			
	AH	US-			
	AI	US-			
	AJ	US-			
	AK	US-			
	AL	US-			
	AM	US-			
	AN	US-			
	AO	US-			
	AP	US-			
	AQ	US-			

**FOREIGN PATENT DOCUMENTS**

Examiner Initials	Cite No.	Foreign Patent Document	Publication Date	Patentee or Applicant	Pages, Column, Lines, Where Relevant Passages Or Relevant Figures Appear	English Language Translation Attached
	AR					
	AS					
	AT					
	AU					

Examiner  
SignatureDate  
Considered